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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

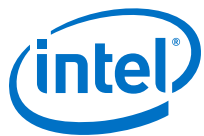
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

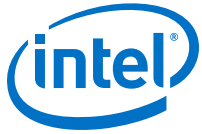
Details

Product Status	Active
Number of LABs/CLBs	125
Number of Logic Elements/Cells	2000
Total RAM Bits	110592
Number of I/O	27
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	36-UFPGA, WLCSP
Supplier Device Package	36-WLCSP (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/intel/10m02dcv36i7g



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Condition (V)	Overshoot Duration as % of High Time	Unit
4.32	2.6	%
4.37	1.6	%
4.42	1.0	%
4.47	0.6	%
4.52	0.3	%
4.57	0.2	%

Recommended Operating Conditions

This section lists the functional operation limits for the AC and DC parameters for Intel MAX 10 devices. The tables list the steady-state voltage values expected from Intel MAX 10 devices. Power supply ramps must all be strictly monotonic, without plateaus.

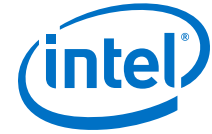
Single Supply Devices Power Supplies Recommended Operating Conditions

Table 6. Power Supplies Recommended Operating Conditions for Intel MAX 10 Single Supply Devices

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V _{CC_ONE} ⁽¹⁾	Supply voltage for core and periphery through on-die voltage regulator	—	2.85/3.135	3.0/3.3	3.15/3.465	V
V _{CCIO} ⁽²⁾	Supply voltage for input and output buffers	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
continued...						

(1) V_{CCA} must be connected to V_{CC_ONE} through a filter.

(2) V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities.



Symbol	Parameter	Condition	Min	Typ	Max	Unit
$V_{CCA}^{(1)}$	Supply voltage for PLL regulator and ADC block (analog)	1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
		—	2.85/3.135	3.0/3.3	3.15/3.465	V

Dual Supply Devices Power Supplies Recommended Operating Conditions

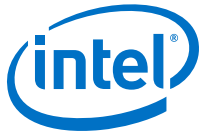
Table 7. Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V_{CC}	Supply voltage for core and periphery	—	1.15	1.2	1.25	V
$V_{CCIO}^{(3)}$	Supply voltage for input and output buffers	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
		1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
$V_{CCA}^{(4)}$	Supply voltage for PLL regulator (analog)	—	2.375	2.5	2.625	V
$V_{CCD_PLL}^{(5)}$	Supply voltage for PLL regulator (digital)	—	1.15	1.2	1.25	V
V_{CCA_ADC}	Supply voltage for ADC analog block	—	2.375	2.5	2.625	V
V_{CCINT}	Supply voltage for ADC digital block	—	1.15	1.2	1.25	V

⁽³⁾ V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities.

⁽⁴⁾ All V_{CCA} pins must be powered to 2.5 V (even when PLLs are not used), and must be powered up and powered down at the same time.

⁽⁵⁾ V_{CCD_PLL} must always be connected to V_{CC} through a decoupling capacitor and ferrite bead.



Recommended Operating Conditions

Table 8. Recommended Operating Conditions for Intel MAX 10 Devices

Symbol	Parameter	Condition	Min	Max	Unit
V _I	DC input voltage	—	−0.5	3.6	V
V _O	Output voltage for I/O pins	—	0	V _{CCIO}	V
T _J	Operating junction temperature	Commercial	0	85	°C
		Industrial	−40 ⁽⁶⁾	100	°C
		Automotive	−40 ⁽⁶⁾	125	°C
t _{RAMP}	Power supply ramp time	—	(7)	10	ms
I _{Diode}	Magnitude of DC current across PCI* clamp diode when enabled	—	—	10	mA

Programming/Erasure Specifications

Table 9. Programming/Erasure Specifications for Intel MAX 10 Devices

This table shows the programming cycles and data retention duration of the user flash memory (UFM) and configuration flash memory (CFM) blocks.

For more information about data retention duration with 10,000 programming cycles for automotive temperature devices, contact your Intel quality representative.

Erase and reprogram cycles (E/P) ⁽⁸⁾ (Cycles/page)	Temperature (°C)	Data retention duration (Years)
10,000	85	20
10,000	100	10

⁽⁶⁾ −40°C is only applicable to Start of Test, when the device is powered-on. The device does not stay at the minimum junction temperature for a long time.

⁽⁷⁾ There is no absolute minimum value for the ramp time requirement. Intel characterized the minimum ramp time at 200 µs.

⁽⁸⁾ The number of E/P cycles applies to the smallest possible flash block that can be erased or programmed in each Intel MAX 10 device. Each Intel MAX 10 device has multiple flash pages per device.

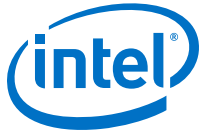


Table 11. ADC_VREF Pin Leakage Current for Intel MAX 10 Devices

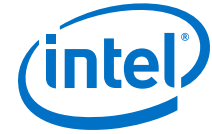
Symbol	Parameter	Condition	Min	Max	Unit
I _{adc_vref}	ADC_VREF pin leakage current	Single supply mode	—	10	μA
		Dual supply mode	—	20	μA

Bus Hold Parameters

Bus hold retains the last valid logic state after the source driving it either enters the high impedance state or is removed. Each I/O pin has an option to enable bus hold in user mode. Bus hold is always disabled in configuration mode.

Table 12. Bus Hold Parameters for Intel MAX 10 Devices

Parameter	Condition	V _{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold low, sustaining current	V _{IN} > V _{IL} (maximum)	8	—	12	—	30	—	50	—	70	—	70	—	μA
Bus-hold high, sustaining current	V _{IN} < V _{IH} (minimum)	–8	—	–12	—	–30	—	–50	—	–70	—	–70	—	μA
Bus-hold low, overdrive current	0 V < V _{IN} < V _{CCIO}	—	125	—	175	—	200	—	300	—	500	—	500	μA
Bus-hold high, overdrive current	0 V < V _{IN} < V _{CCIO}	—	–125	—	–175	—	–200	—	–300	—	–500	—	–500	μA
Bus-hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V



- Subscript x refers to both V and T.
- ΔR_V is variation of resistance with voltage.
- ΔR_T is variation of resistance with temperature.
- dR/dT is the change percentage of resistance with temperature after calibration at device power-up.
- dR/dV is the change percentage of resistance with voltage after calibration at device power-up.
- V_1 is the initial voltage.
- V_2 is final voltage.

The following figure shows the example to calculate the change of 50 Ω I/O impedance from 25°C at 3.0 V to 85°C at 3.15 V.

Figure 2. Example for OCT Resistance Calculation after Calibration at Device Power-Up

$$\Delta R_V = (3.15 - 3) \times 1000 \times -0.027 = -4.05$$

$$\Delta R_T = (85 - 25) \times 0.25 = 15$$

Because ΔR_V is negative,

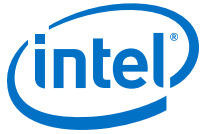
$$MF_V = 1/(4.05/100 + 1) = 0.961$$

Because ΔR_T is positive,

$$MF_T = 15/100 + 1 = 1.15$$

$$MF = 0.961 \times 1.15 = 1.105$$

$$R_{final} = 50 \times 1.105 = 55.25\Omega$$



Pin Capacitance

Table 16. Pin Capacitance for Intel MAX 10 Devices

Symbol	Parameter	Maximum	Unit
C _{I0B}	Input capacitance on bottom I/O pins	8	pF
C _{I0LRT}	Input capacitance on left/right/top I/O pins	7	pF
C _{LVDSB}	Input capacitance on bottom I/O pins with dedicated LVDS output ⁽⁹⁾	8	pF
C _{ADCL}	Input capacitance on left I/O pins with ADC input ⁽¹⁰⁾	9	pF
C _{VREFLRT}	Input capacitance on left/right/top dual purpose V _{REF} pin when used as V _{REF} or user I/O pin ⁽¹¹⁾	48	pF
C _{VREFB}	Input capacitance on bottom dual purpose V _{REF} pin when used as V _{REF} or user I/O pin	50	pF
C _{CLKB}	Input capacitance on bottom dual purpose clock input pins ⁽¹²⁾	7	pF
C _{CLKLRT}	Input capacitance on left/right/top dual purpose clock input pins ⁽¹²⁾	6	pF

Internal Weak Pull-Up Resistor

All I/O pins, except configuration, test, and JTAG pins, have an option to enable weak pull-up.

⁽⁹⁾ Dedicated LVDS output buffer is only available at bottom I/O banks.

⁽¹⁰⁾ ADC pins are only available at left I/O banks.

⁽¹¹⁾ When V_{REF} pin is used as regular input or output, F_{max} performance is reduced due to higher pin capacitance. Using the V_{REF} pin capacitance specification from device datasheet, perform SI analysis on your board setup to determine the F_{max} of your system.

⁽¹²⁾ 10M40 and 10M50 devices have dual purpose clock input pins at top/bottom I/O banks.

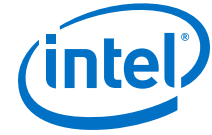
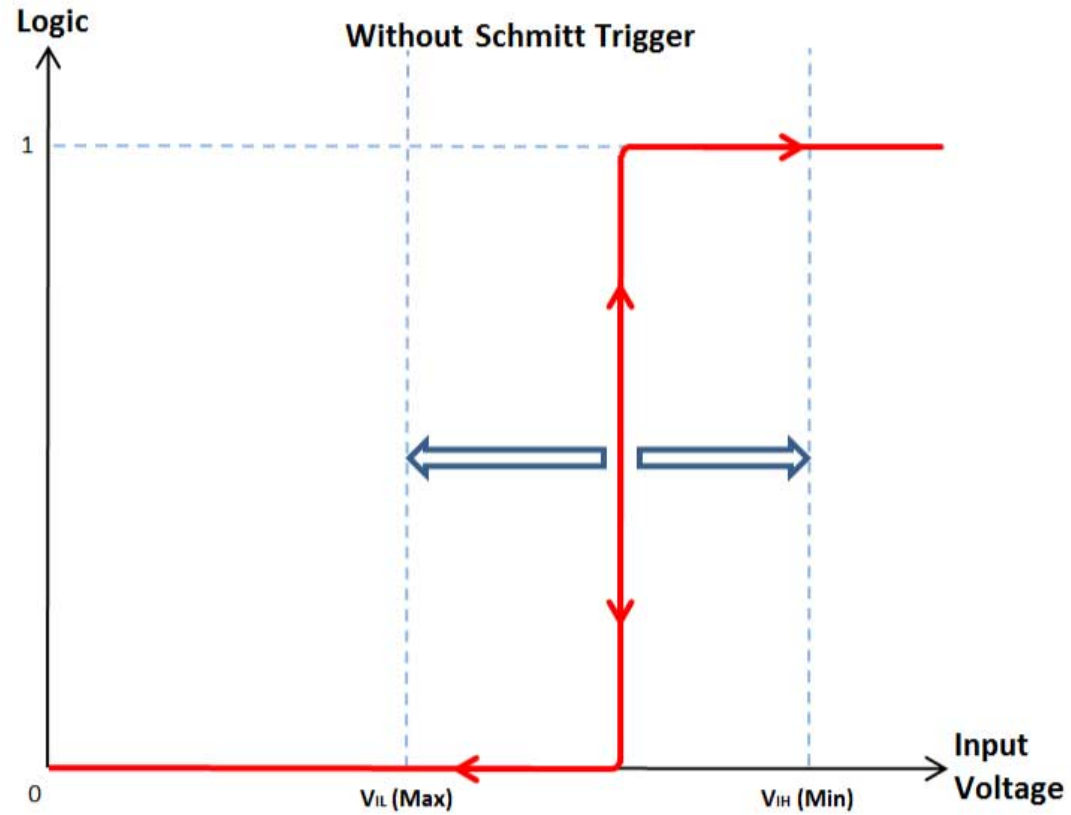
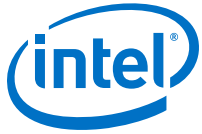


Figure 3. LVTTL/LVCMOS Input Standard Voltage Diagram





Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications

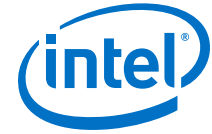
Table 21. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{REF} (V)			V _{TT} (V) ⁽¹⁴⁾		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}
SSTL-135 Class I, II	1.283	1.35	1.45	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 × V _{CCIO} ⁽¹⁵⁾	0.5 × V _{CCIO} ⁽¹⁵⁾	0.52 × V _{CCIO} ⁽¹⁵⁾	—	0.5 × V _{CCIO}	—
				0.47 × V _{CCIO} ⁽¹⁶⁾	0.5 × V _{CCIO} ⁽¹⁶⁾	0.53 × V _{CCIO} ⁽¹⁶⁾			
HSUL-12	1.14	1.2	1.3	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	—	—	—

⁽¹⁴⁾ V_{TT} of transmitting device must track V_{REF} of the receiving device.

⁽¹⁵⁾ Value shown refers to DC input reference voltage, V_{REF(DC)}.

⁽¹⁶⁾ Value shown refers to AC input reference voltage, V_{REF(AC)}.



Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications

Table 22. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Intel MAX 10 Devices

To meet the I_{OL} and I_{OH} specifications, you must set the current strength settings accordingly. For example, to meet the SSTL-15 Class I specification (8 mA), you should set the current strength settings to 8 mA. Setting at lower current strength may not meet the I_{OL} and I_{OH} specifications in the datasheet.

I/O Standard	$V_{IL(DC)} (V)$		$V_{IH(DC)} (V)$		$V_{IL(AC)} (V)$		$V_{IH(AC)} (V)$		$V_{OL} (V)$	$V_{OH} (V)$	$I_{OL} (mA)$	$I_{OH} (mA)$
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
SSTL-2 Class I	—	$V_{REF} - 0.18$	$V_{REF} + 0.18$	—	—	$V_{REF} - 0.31$	$V_{REF} + 0.31$	—	$V_{TT} - 0.57$	$V_{TT} + 0.57$	8.1	-8.1
SSTL-2 Class II	—	$V_{REF} - 0.18$	$V_{REF} + 0.18$	—	—	$V_{REF} - 0.31$	$V_{REF} + 0.31$	—	$V_{TT} - 0.76$	$V_{TT} + 0.76$	16.4	-16.4
SSTL-18 Class I	—	$V_{REF} - 0.125$	$V_{REF} + 0.125$	—	—	$V_{REF} - 0.25$	$V_{REF} + 0.25$	—	$V_{TT} - 0.475$	$V_{TT} + 0.475$	6.7	-6.7
SSTL-18 Class II	—	$V_{REF} - 0.125$	$V_{REF} + 0.125$	—	—	$V_{REF} - 0.25$	$V_{REF} + 0.25$	—	0.28	$V_{CCIO} - 0.28$	13.4	-13.4
SSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	—	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	8	-8
SSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	—	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	16	-16
SSTL-135	—	$V_{REF} - 0.09$	$V_{REF} + 0.09$	—	—	$V_{REF} - 0.16$	$V_{REF} + 0.16$	—	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	—	—
HSTL-18 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	8	-8
HSTL-18 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	16	-16
HSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	8	-8
HSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	16	-16

continued...



I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)		V _{IH(AC)} (V)		V _{OL} (V)	V _{OH} (V)	I _{OL} (mA)	I _{OH} (mA)
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
HSTL-12 Class I	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14
HSUL-12	—	V _{REF} - 0.13	V _{REF} + 0.13	—	—	V _{REF} - 0.22	V _{REF} + 0.22	—	0.1 × V _{CCIO}	0.9 × V _{CCIO}	—	—

Differential SSTL I/O Standards Specifications

Differential SSTL requires a V_{REF} input.

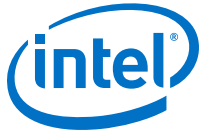
Table 23. Differential SSTL I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{Swing(DC)} (V)		V _{X(AC)} (V)			V _{Swing(AC)} (V)	
	Min	Typ	Max	Min	Max ⁽¹⁷⁾	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V _{CCIO}	V _{CCIO} /2 - 0.2	—	V _{CCIO} /2 + 0.2	0.7	V _{CCIO}
SSTL-18 Class I, II	1.7	1.8	1.9	0.25	V _{CCIO}	V _{CCIO} /2 - 0.175	—	V _{CCIO} /2 + 0.175	0.5	V _{CCIO}
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	V _{CCIO} /2 - 0.15	—	V _{CCIO} /2 + 0.15	2(V _{IH(AC)} - V _{REF})	2(V _{IL(AC)} - V _{REF})
SSTL-135	1.283	1.35	1.45	0.18	—	V _{REF} - 0.135	0.5 × V _{CCIO}	V _{REF} + 0.135	2(V _{IH(AC)} - V _{REF})	2(V _{IL(AC)} - V _{REF})

Differential HSTL and HSUL I/O Standards Specifications

Differential HSTL requires a V_{REF} input.

⁽¹⁷⁾ The maximum value for V_{SWING(DC)} is not defined. However, each single-ended signal needs to be within the respective single-ended limits (V_{IH(DC)} and V_{IL(DC)}).



Symbol	Parameter	Condition	Min	Typ	Max	Unit
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	—	±50	ps
t_{ARESET}	Minimum pulse width on areset signal.	—	10	—	—	ns
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for PLLs	—	—	3.5 ⁽³²⁾	—	SCANCLK cycles
$f_{SCANCLK}$	scanclk frequency	—	—	—	100	MHz

Table 28. PLL Specifications for Intel MAX 10 Single Supply Devices

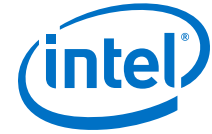
For V36 package, the PLL specification is based on single supply devices.

Symbol	Parameter	Condition	Max	Unit
$t_{OUTJITTER_PERIOD_DEDCLK}$ ⁽³¹⁾	Dedicated clock output period jitter	$F_{OUT} \geq 100$ MHz	660	ps
		$F_{OUT} < 100$ MHz	66	mUI
$t_{OUTJITTER_CCJ_DEDCLK}$ ⁽³¹⁾	Dedicated clock output cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	660	ps
		$F_{OUT} < 100$ MHz	66	mUI

Table 29. PLL Specifications for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Max	Unit
$t_{OUTJITTER_PERIOD_DEDCLK}$ ⁽³¹⁾	Dedicated clock output period jitter	$F_{OUT} \geq 100$ MHz	300	ps
		$F_{OUT} < 100$ MHz	30	mUI
$t_{OUTJITTER_CCJ_DEDCLK}$ ⁽³¹⁾	Dedicated clock output cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	300	ps
		$F_{OUT} < 100$ MHz	30	mUI

⁽³²⁾ With 100 MHz scanclk frequency.



Dual Supply Devices ADC Performance Specifications

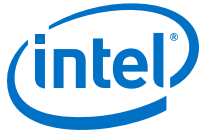
Table 35. ADC Performance Specifications for Intel MAX 10 Dual Supply Devices

Parameter		Symbol	Condition	Min	Typ	Max	Unit
ADC resolution		—	—	—	—	12	bits
Analog supply voltage		V_{CCA_ADC}	—	2.375	2.5	2.625	V
Digital supply voltage		V_{CCINT}	—	1.15	1.2	1.25	V
External reference voltage		V_{REF}	—	$V_{CCA_ADC} - 0.5$	—	V_{CCA_ADC}	V
Sampling rate		F_S	Accumulative sampling rate	—	—	1	MSPS
Operating junction temperature range		T_J	—	-40	25	125	°C
Analog input voltage		V_{IN}	Prescaler disabled	0	—	V_{REF}	V
			Prescaler enabled ⁽⁴²⁾	0	—	3	V
Analog supply current (DC)		I_{ACC_ADC}	Average current	—	275	450	μA
Digital supply current (DC)		I_{CCINT}	Average current	—	65	150	μA
Input resistance		R_{IN}	—	—	⁽⁴³⁾	—	—
Input capacitance		C_{IN}	—	—	⁽⁴³⁾	—	—
DC Accuracy	Offset error and drift	E_{offset}	Prescaler disabled	-0.2	—	0.2	%FS
			Prescaler enabled	-0.5	—	0.5	%FS
	Gain error and drift	E_{gain}	Prescaler disabled	-0.5	—	0.5	%FS
			Prescaler enabled	-0.75	—	0.75	%FS
	Differential non linearity	DNL	External V_{REF} , no missing code	-0.9	—	0.9	LSB

continued...

⁽⁴²⁾ Prescaler function divides the analog input voltage by half. The analog input handles up to 3 V input for the Intel MAX 10 dual supply devices.

⁽⁴³⁾ Download the SPICE models for simulation.



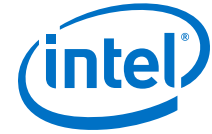
True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications

Single Supply Devices True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications

Table 37. True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices

True **RSDS** transmitter is only supported at bottom I/O banks. Emulated **RSDS** transmitter is supported at the output pin of all I/O banks.

Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HSCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	—	50	5	—	50	5	—	50	MHz
		×8	5	—	50	5	—	50	5	—	50	MHz
		×7	5	—	50	5	—	50	5	—	50	MHz
		×4	5	—	50	5	—	50	5	—	50	MHz
		×2	5	—	50	5	—	50	5	—	50	MHz
		×1	5	—	100	5	—	100	5	—	100	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	—	100	100	—	100	100	—	100	Mbps
		×8	80	—	100	80	—	100	80	—	100	Mbps
		×7	70	—	100	70	—	100	70	—	100	Mbps
		×4	40	—	100	40	—	100	40	—	100	Mbps
		×2	20	—	100	20	—	100	20	—	100	Mbps
		×1	10	—	100	10	—	100	10	—	100	Mbps
f _{HSCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	—	50	5	—	50	5	—	50	MHz
		×8	5	—	50	5	—	50	5	—	50	MHz
		×7	5	—	50	5	—	50	5	—	50	MHz
		×4	5	—	50	5	—	50	5	—	50	MHz
		×2	5	—	50	5	—	50	5	—	50	MHz
		×1	5	—	100	5	—	100	5	—	100	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	—	100	100	—	100	100	—	100	Mbps
continued...												



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×8	80	—	100	80	—	100	80	—	100	Mbps
		×7	70	—	100	70	—	100	70	—	100	Mbps
		×4	40	—	100	40	—	100	40	—	100	Mbps
		×2	20	—	100	20	—	100	20	—	100	Mbps
		×1	10	—	100	10	—	100	10	—	100	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵⁵⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _x Jitter ⁽⁵⁶⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵⁵⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁵⁶⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



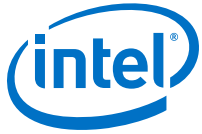
True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications

Table 40. True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices

True **mini-LVDS** transmitter is only supported at the bottom I/O banks. Emulated **mini-LVDS_E_3R** transmitter is supported at the output pin of all I/O banks.

Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	—	155	5	—	155	5	—	155	MHz
		×8	5	—	155	5	—	155	5	—	155	MHz
		×7	5	—	155	5	—	155	5	—	155	MHz
		×4	5	—	155	5	—	155	5	—	155	MHz
		×2	5	—	155	5	—	155	5	—	155	MHz
		×1	5	—	310	5	—	310	5	—	310	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	—	310	100	—	310	100	—	310	Mbps
		×8	80	—	310	80	—	310	80	—	310	Mbps
		×7	70	—	310	70	—	310	70	—	310	Mbps
		×4	40	—	310	40	—	310	40	—	310	Mbps
		×2	20	—	310	20	—	310	20	—	310	Mbps
		×1	10	—	310	10	—	310	10	—	310	Mbps
f _{HCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	—	150	5	—	150	5	—	150	MHz
		×8	5	—	150	5	—	150	5	—	150	MHz
		×7	5	—	150	5	—	150	5	—	150	MHz
		×4	5	—	150	5	—	150	5	—	150	MHz
		×2	5	—	150	5	—	150	5	—	150	MHz
		×1	5	—	300	5	—	300	5	—	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	—	300	100	—	300	100	—	300	Mbps
		×8	80	—	300	80	—	300	80	—	300	Mbps

continued...



True LVDS Transmitter Timing

Single Supply Devices True LVDS Transmitter Timing Specifications

Table 41. True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices

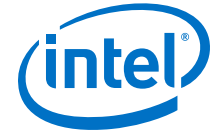
True LVDS transmitter is only supported at the bottom I/O banks.

Symbol	Parameter	Mode	-C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HCLK}	Input clock frequency	×10	5	—	145	5	—	100	5	—	100	MHz
		×8	5	—	145	5	—	100	5	—	100	MHz
		×7	5	—	145	5	—	100	5	—	100	MHz
		×4	5	—	145	5	—	100	5	—	100	MHz
		×2	5	—	145	5	—	100	5	—	100	MHz
		×1	5	—	290	5	—	200	5	—	200	MHz
HSIODR	Data rate	×10	100	—	290	100	—	200	100	—	200	Mbps
		×8	80	—	290	80	—	200	80	—	200	Mbps
		×7	70	—	290	70	—	200	70	—	200	Mbps
		×4	40	—	290	40	—	200	40	—	200	Mbps
		×2	20	—	290	20	—	200	20	—	200	Mbps
		×1	10	—	290	10	—	200	10	—	200	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁶³⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁶⁴⁾	Output jitter	—	—	—	1,000	—	—	1,000	—	—	1,000	ps

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⁽⁶³⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁶⁴⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



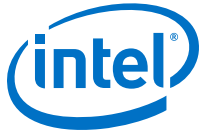
Dual Supply Devices Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications

Table 44. Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices

Emulated **LVDS_E_3R**, **SLVS**, and **Sub-LVDS** transmitters are supported at the output pin of all I/O banks.

Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	—	300	5	—	275	5	—	275	MHz
		×8	5	—	300	5	—	275	5	—	275	MHz
		×7	5	—	300	5	—	275	5	—	275	MHz
		×4	5	—	300	5	—	275	5	—	275	MHz
		×2	5	—	300	5	—	275	5	—	275	MHz
		×1	5	—	300	5	—	275	5	—	275	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	—	600	100	—	550	100	—	550	Mbps
		×8	80	—	600	80	—	550	80	—	550	Mbps
		×7	70	—	600	70	—	550	70	—	550	Mbps
		×4	40	—	600	40	—	550	40	—	550	Mbps
		×2	20	—	600	20	—	550	20	—	550	Mbps
		×1	10	—	300	10	—	275	10	—	275	Mbps
f _{HCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	—	150	5	—	150	5	—	150	MHz
		×8	5	—	150	5	—	150	5	—	150	MHz
		×7	5	—	150	5	—	150	5	—	150	MHz
		×4	5	—	150	5	—	150	5	—	150	MHz
		×2	5	—	150	5	—	150	5	—	150	MHz
		×1	5	—	300	5	—	300	5	—	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	—	300	100	—	300	100	—	300	Mbps
		×8	80	—	300	80	—	300	80	—	300	Mbps

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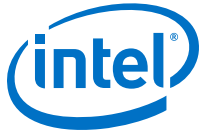
Device	CFM Data Size (bits)	
	Without Memory Initialization	With Memory Initialization
10M25	4,140,000	4,780,000
10M40	7,840,000	9,670,000
10M50	7,840,000	9,670,000

Internal Configuration Time

The internal configuration time measurement is from the rising edge of nSTATUS signal to the rising edge of CONF_DONE signal.

Table 53. Internal Configuration Time for Intel MAX 10 Devices (Uncompressed .rbf)

Device	Internal Configuration Time (ms)							
	Unencrypted				Encrypted			
	Without Memory Initialization		With Memory Initialization		Without Memory Initialization		With Memory Initialization	
	Min	Max	Min	Max	Min	Max	Min	Max
10M02	0.3	1.7	—	—	1.7	5.4	—	—
10M04	0.6	2.7	1.0	3.4	5.0	15.0	6.8	19.6
10M08	0.6	2.7	1.0	3.4	5.0	15.0	6.8	19.6
10M16	1.1	3.7	1.4	4.5	9.3	25.3	11.7	31.5
10M25	1.0	3.7	1.3	4.4	14.0	38.1	16.9	45.7
10M40	2.6	6.9	3.2	9.8	41.5	112.1	51.7	139.6
10M50	2.6	6.9	3.2	9.8	41.5	112.1	51.7	139.6



Date	Version	Changes
May 2015	2015.05.04	• Updated a note to V_{CCIO} for both single supply and dual supply power supplies recommended operating conditions tables. Note updated: V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities. • Updated Example for OCT Resistance Calculation after Calibration at Device Power-Up. • Removed a note to BLVDS in Differential I/O Standards Specifications for Intel MAX 10 Devices table. BLVDS is now supported in Intel MAX 10 single supply devices. Note removed: BLVDS TX is not supported in single supply devices. • Updated ADC Performance Specifications for both single supply and dual supply devices. — Changed the symbol for Operating junction temperature range parameter from T_A to T_J. — Edited sampling rate maximum value from 1000 kSPS to 1 MSPS. — Added a note to analog input voltage parameter. — Removed input frequency, f_{IN} specification. — Updated the condition for DNL specification: External V_{REF}, no missing code. Added DNL specification for condition: Internal V_{REF}, no missing code. — Added notes to AC accuracy specifications that the value with prescaler enabled is 6dB less than the specification. — Added a note to On-Chip Temperature Sensor (absolute accuracy) parameter about the averaging calculation. • Updated ADC Performance Specifications for Intel MAX 10 Single Supply Devices table. — Added condition for On-Chip Temperature Sensor (absolute accuracy) parameter: with 64 samples averaging. • Updated ADC Performance Specifications for Intel MAX 10 Dual Supply Devices table. — Updated Digital Supply Voltage minimum value from 1.14 V to 1.15 V and maximum value from 1.26 V to 1.25 V. • Updated f_{HCLK} and HSIODR specifications for –A7 speed grade in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices — LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices

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